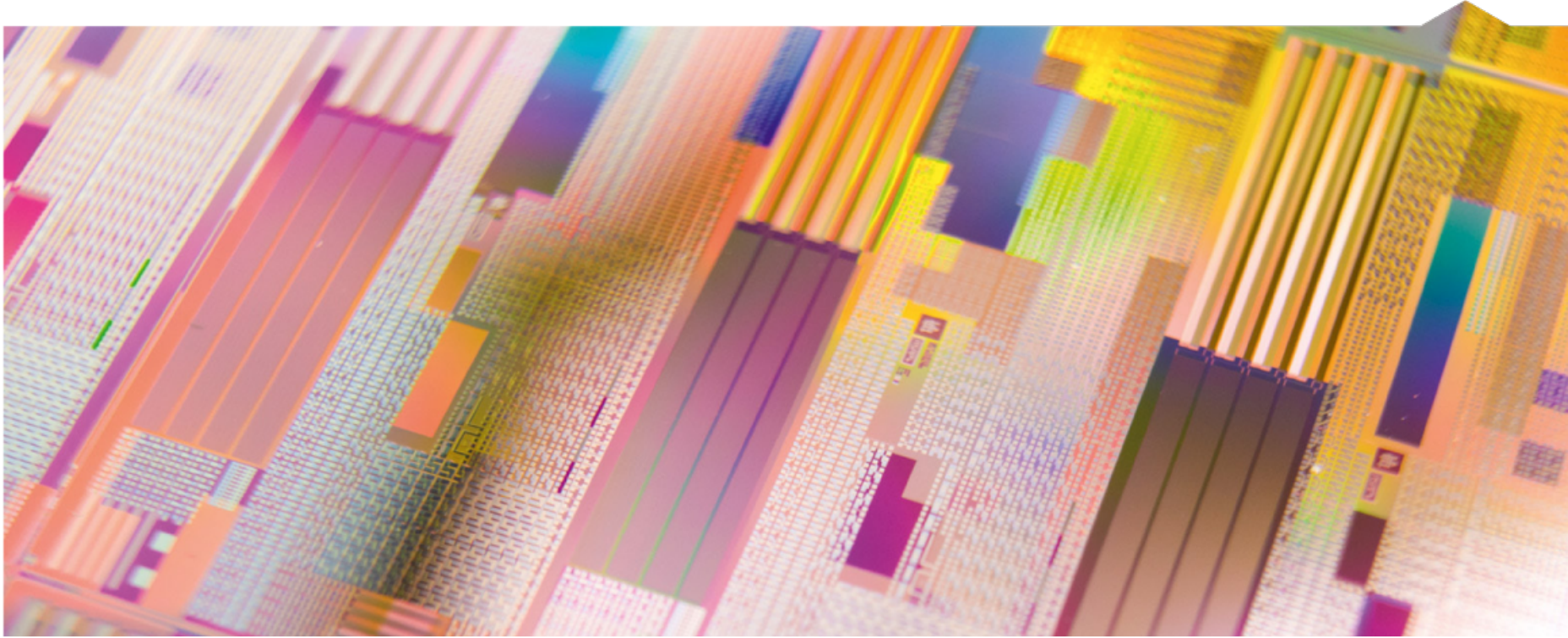




ALD MATERIALS INTEGRATION CHALLENGES

GLEN WILK

› Industry Trends for Materials and Architectures

› Examples of materials innovations

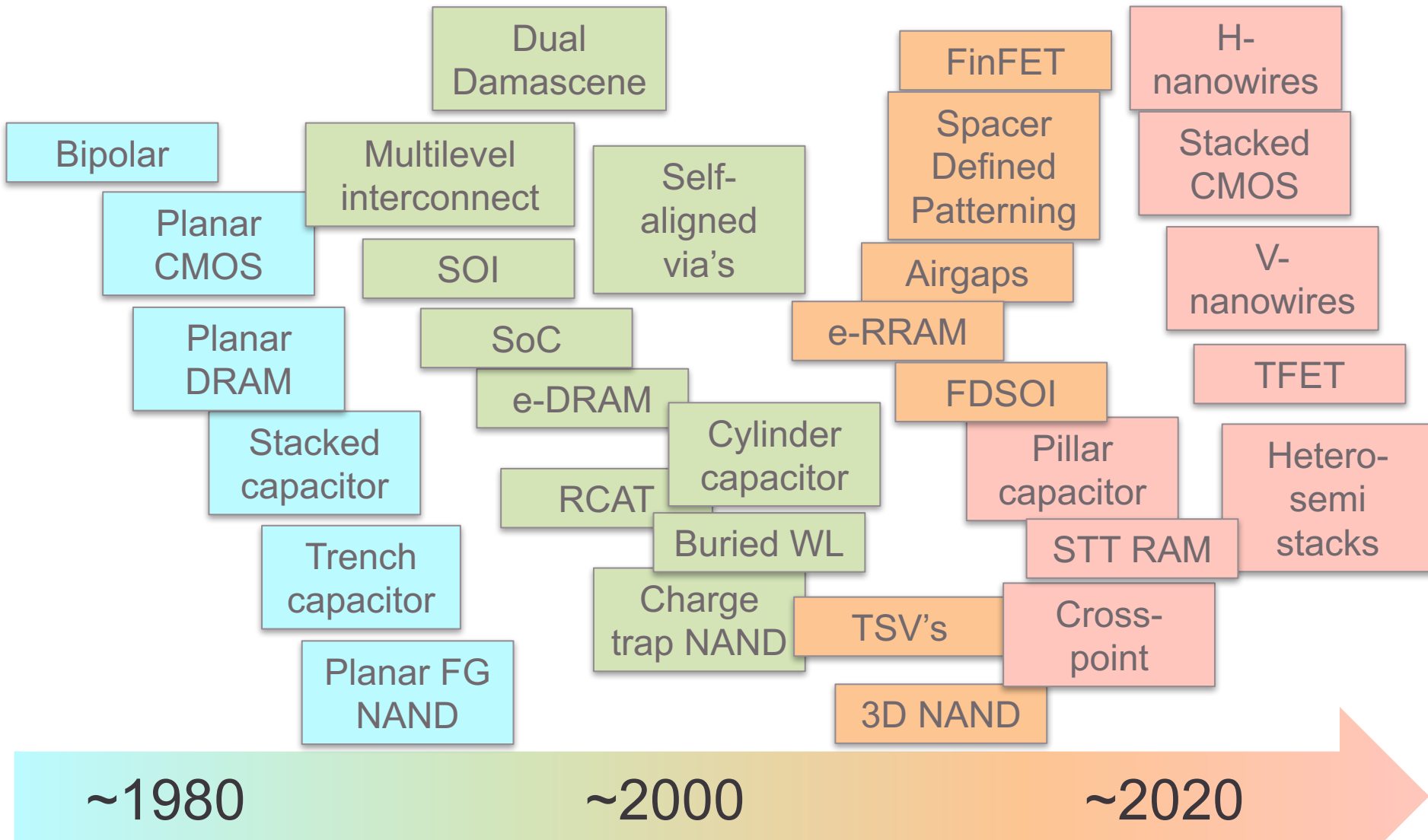
- High-k and metal gate
- Patterning materials
- New spacer materials
- Low thermal budget processes

› Needs from Chemical Suppliers

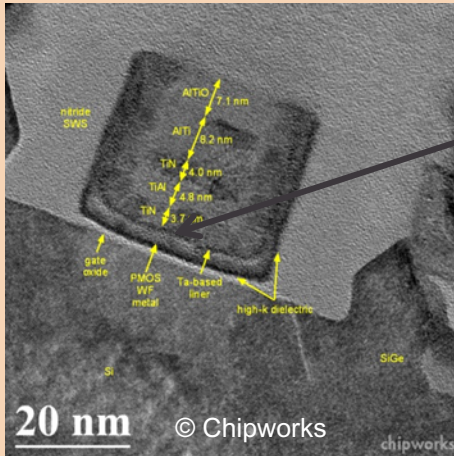
INDUSTRY TRENDS

DRIVE INNOVATION • DELIVER EXCELLENCE 

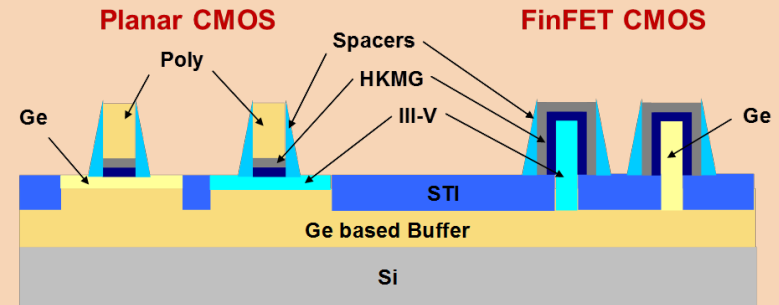
ARCHITECTURAL INNOVATIONS: MOORE'S LAW ENABLERS



Higher Capacitance, Lower Leakage

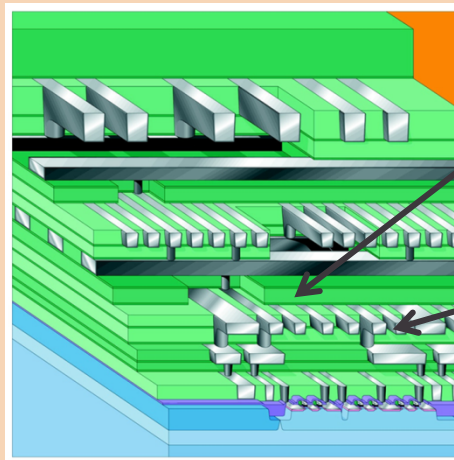


Higher Mobility, Lower Resistance

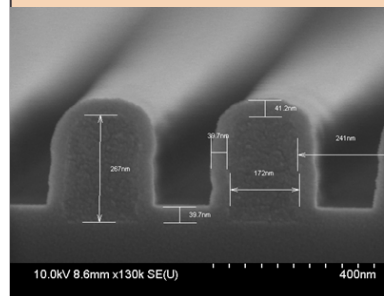


Strain and new Channel Materials
New metal contacts

Less Cross Talk, Faster Interconnect



Smaller Feature Sizes

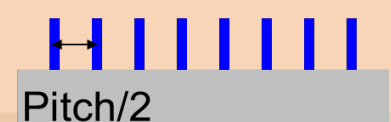


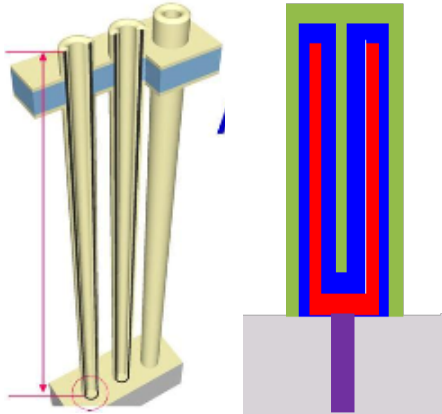
-EUV delays led to more double patterning (SDDP/SDQP)
-EUV will enable many new materials

Conformal SiO₂



Anisotropic Etch





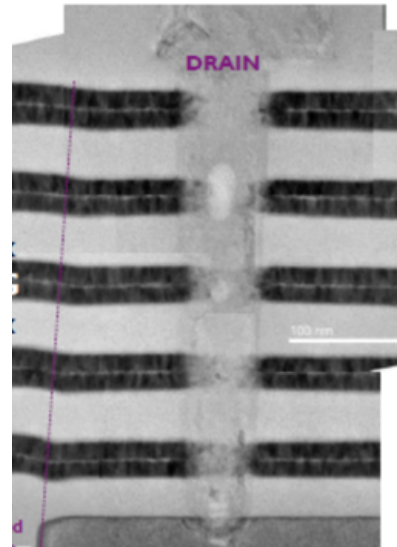
DRAM cell

New materials:

High WF metal for TE
and HK in BO
CT layers

Requirements:

Thickness < 5nm
MG WF > 4.8eV



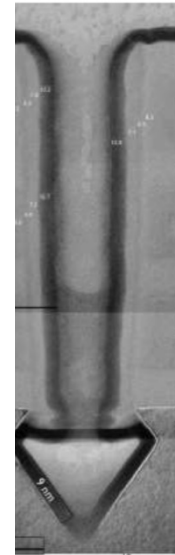
Vertical NAND

New Materials:

Low R metals

Requirements:

$R < 100 \mu\Omega \cdot \text{cm}$
Fluorine free



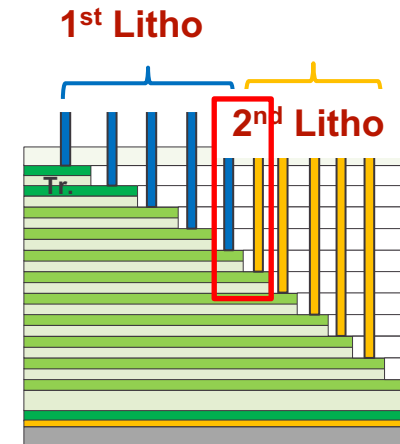
VNAND high-mobility channels

New Materials:

ALD III-V
Conductive oxides

Requirements:

Thickness < 10nm
AR > 50
Thermal stab 800C
Conformality: 95%



Staircase

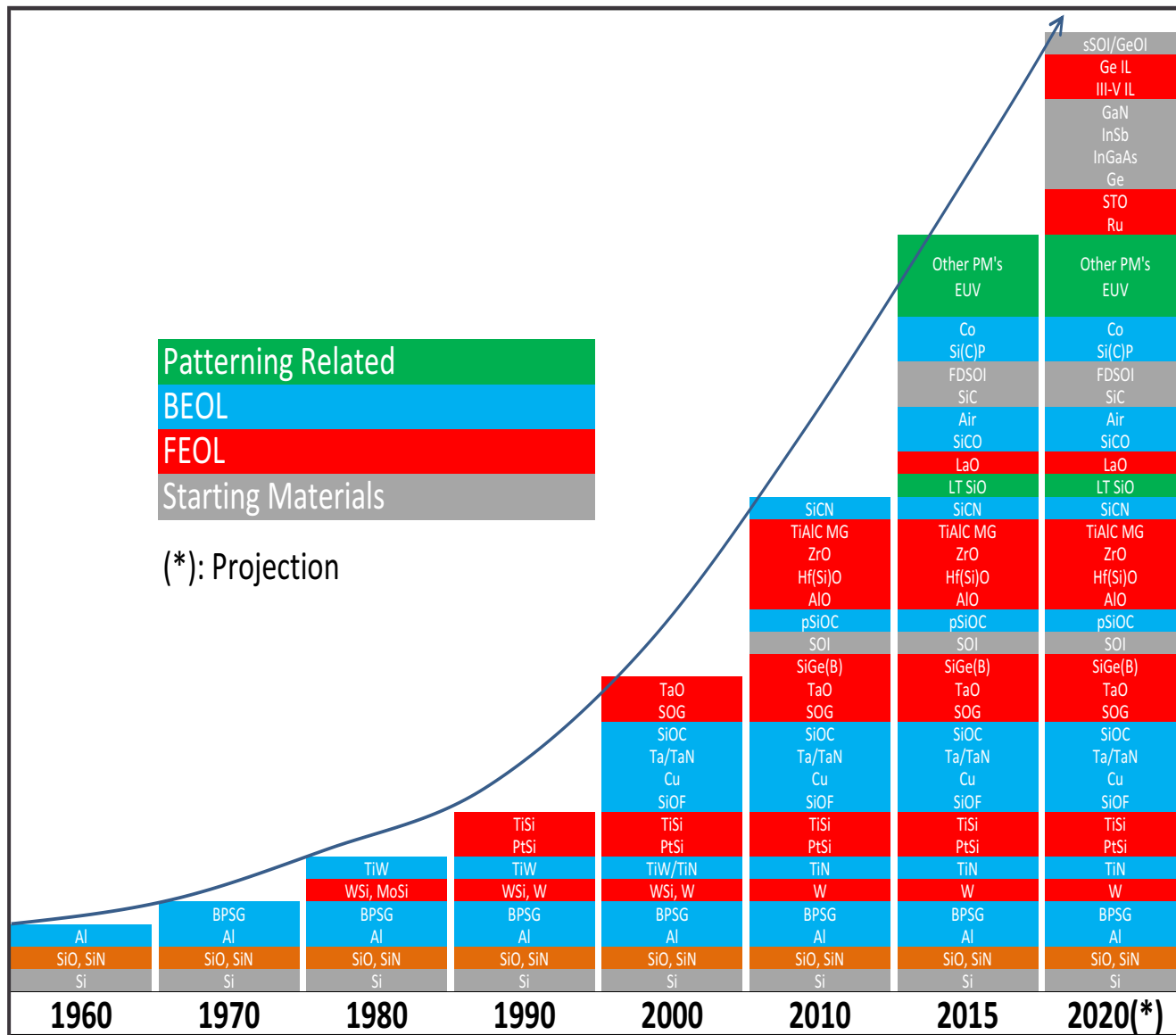
New Materials:

Selective ALD in staircase
ALD a-C protective fill layer
Resist hardening

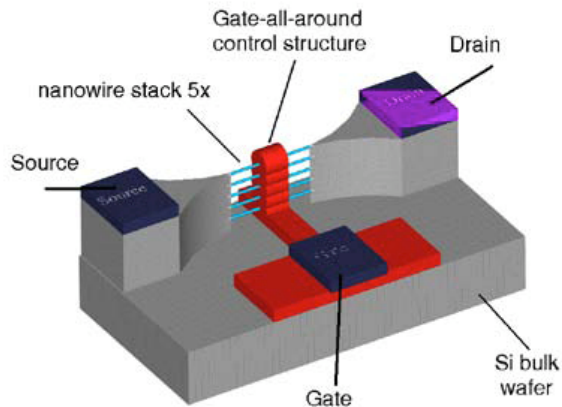
MATERIALS INNOVATIONS

DRIVE INNOVATION • DELIVER EXCELLENCE 

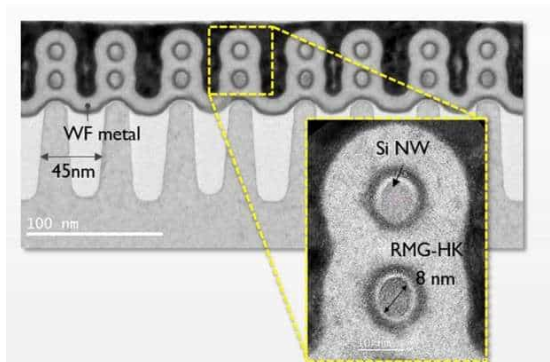
NEW MATERIALS: MOORE'S LAW ENABLERS



THERMAL ALD SOLUTIONS CRITICAL FOR 3D STRUCTURES



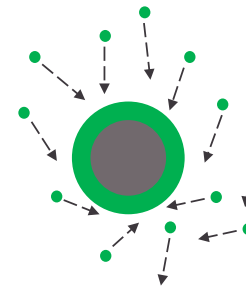
Source: SemiEngineering



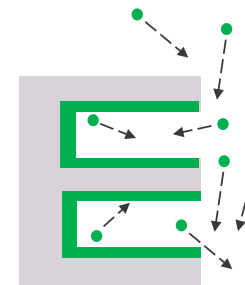
Source: IMEC

- › Move to 3D devices necessitates the use of pure thermal ALD techniques
- › Lower thermal budgets for ALD and PEALD

Thermal ALD

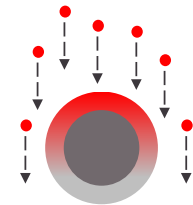


Stoichiometric film regardless of directionality

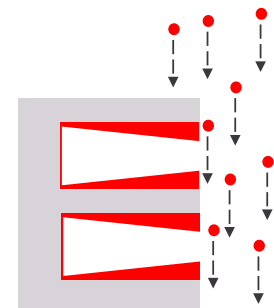


Near perfect step coverage in deep and re-entrant structures

Plasma ALD



Directional nature of reactants results in non-uniform composition



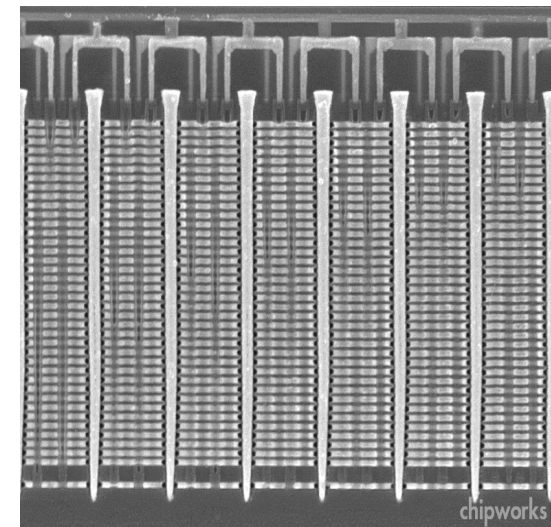
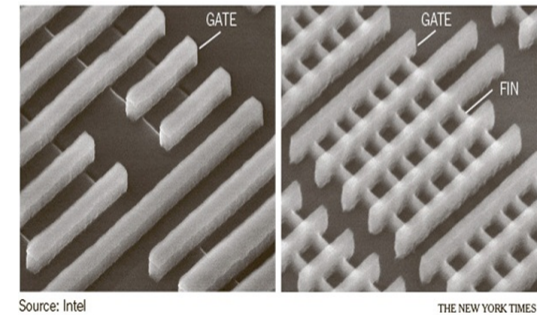
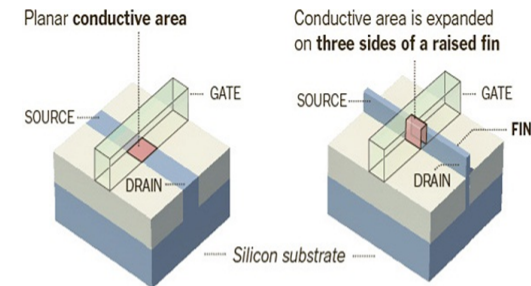
Step coverage limited (especially in re-entrant structures)

› Atomic Layer Deposition separates reactive precursors in time (or space), and grows materials one ‘atomic’ layer at a time

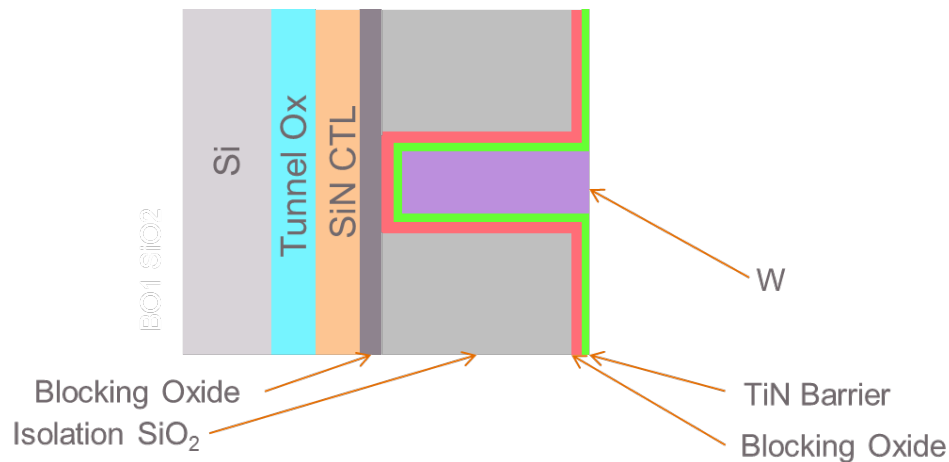
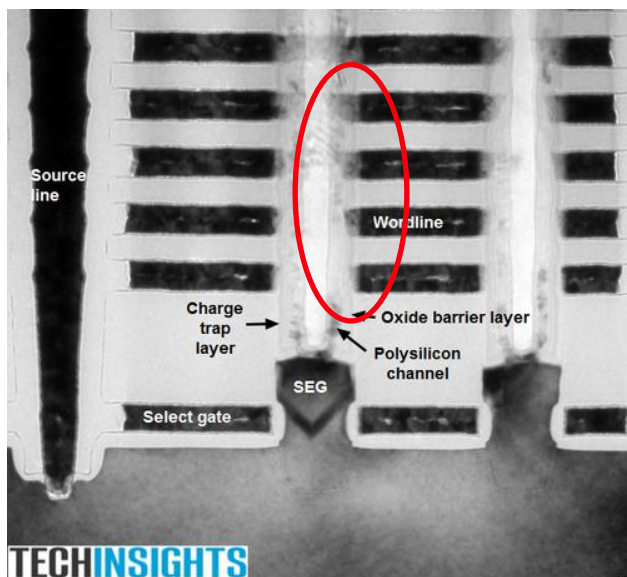
- Superb control of uniformity, conformality, quality, and composition over any topography
- Plasma Enhanced ALD provides high quality materials at lower temperatures
- Need many etch selective materials with wide range of film properties and compositions

› ALD and PEALD are architecture enablers: High Aspect Ratio structures, FinFET, double patterning, VNAND,...

Right: NY Times 2011; http://electroiq.com/chipworks_real_chips_blog/2014/08/04/



METAL FOR VNAND WL FOR VERTICAL & LATERAL PITCH SCALING



› To enable vertical scaling of word line

- Development of ALD TiN with fast-closing layer < 15Å
- Development of F-free ALD processes
- New precursors

CRITICAL ALD SUPPLY CHAIN COMPONENTS

Fundamental
Capability

Process
Performance

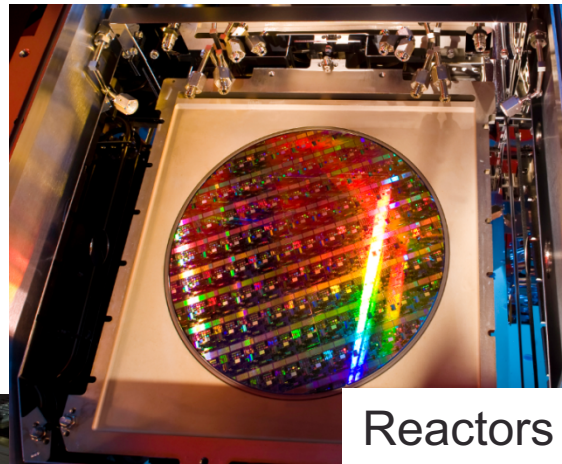
Productivity

Integrated
Process

Final Product
Capability



Precursors



Reactors



High productivity tools

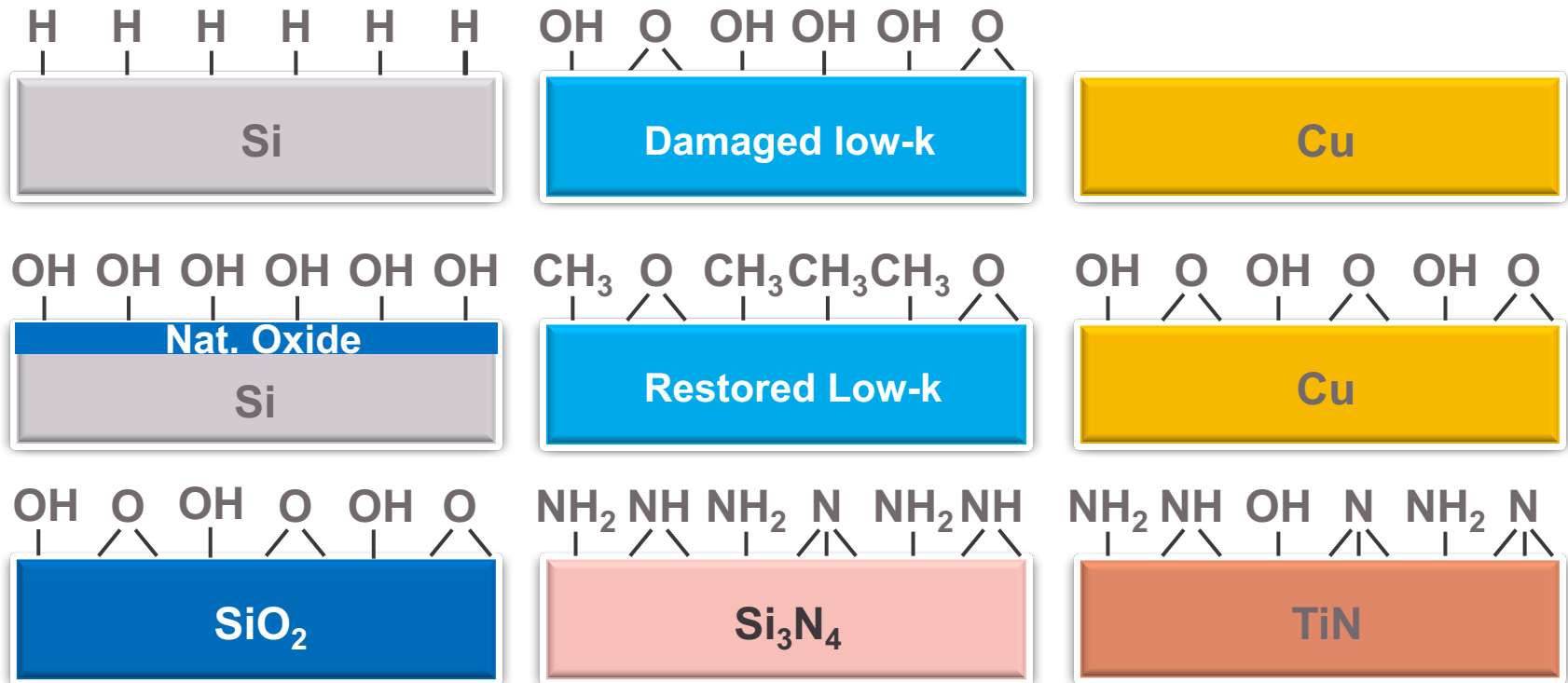


Precursor
Delivery, Valves
and Vessels



Fab facilities,
pumps & abatement

WHAT'S NEXT IN PROCESS INNOVATIONS?



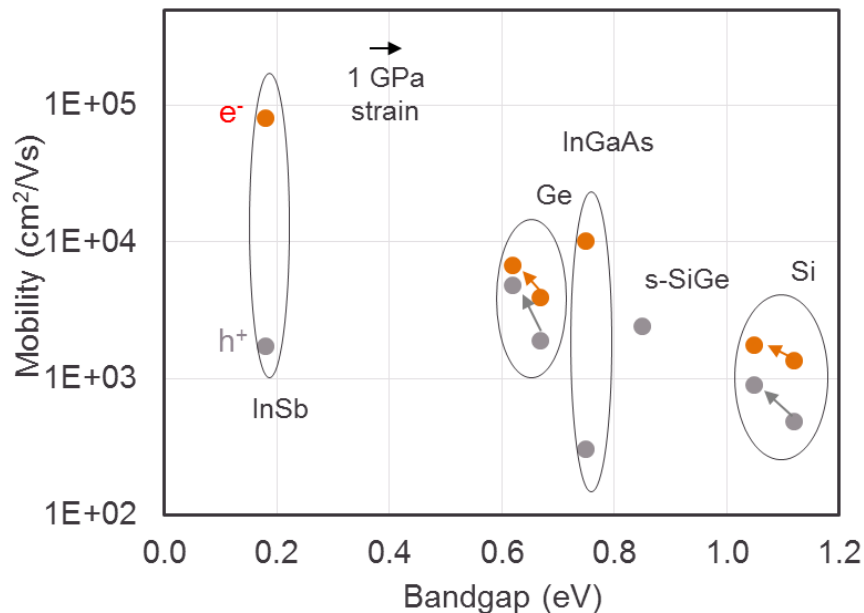
- › The surface sensitivity of ALD and CVD may be ideal to create selective deposition
 - Many potential applications exist in memory, logic, interconnect, and patterning
 - Building templated self-aligned structures: reduction of overlay requirements
- › Strong need for many variations of selective ALD: Metal on Metal, Dielectric on Dielectric, etc.
- › Reversing the reaction to highly selective Atomic Layer Etching

LOW THERMAL BUDGET PROCESSES

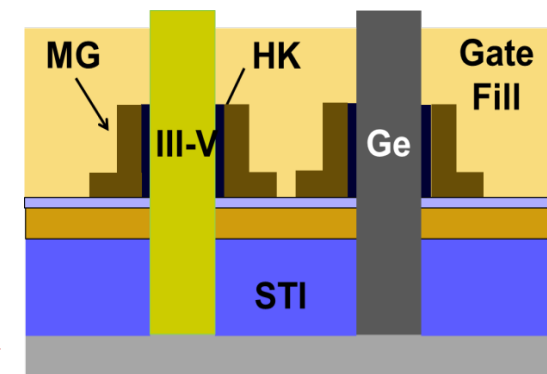
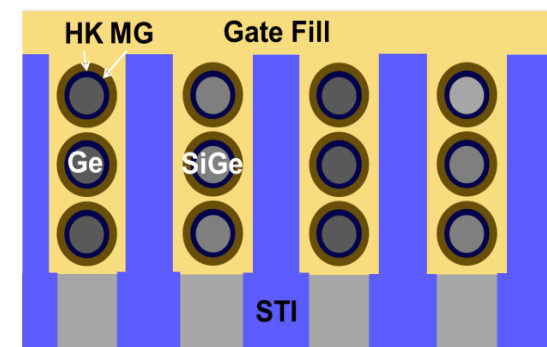
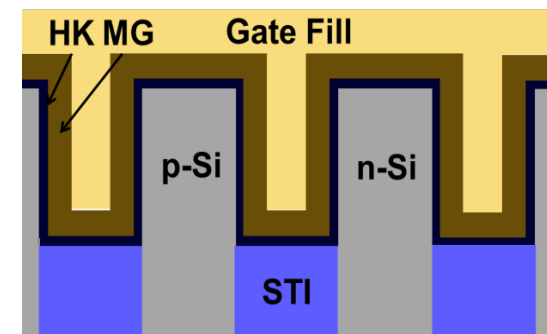
DRIVE INNOVATION • DELIVER EXCELLENCE 

HIGH MOBILITY CHANNEL MATERIALS

- › Voltage scaling requires high mobility channel materials with proper bandgap
- › Introduction will probably be simultaneous with architecture change to nanowires
- › Epitaxy and ALD will be enabling deposition technologies



2011



~2021

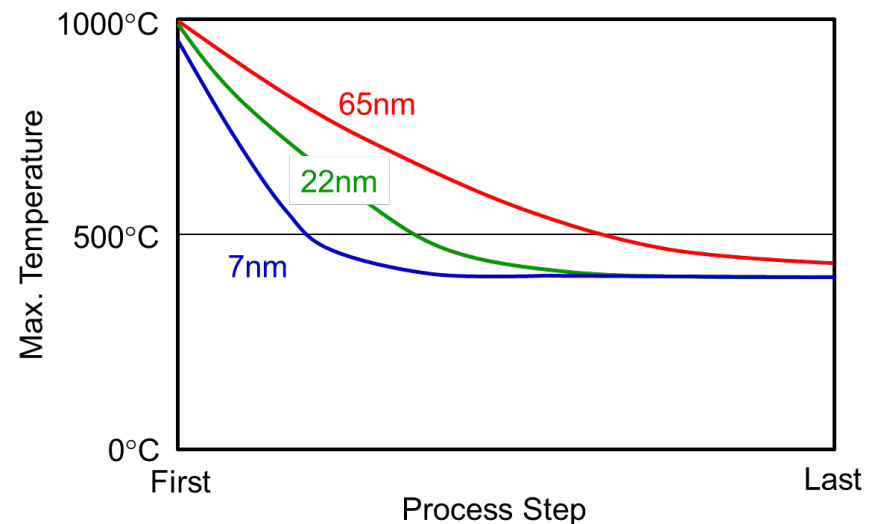
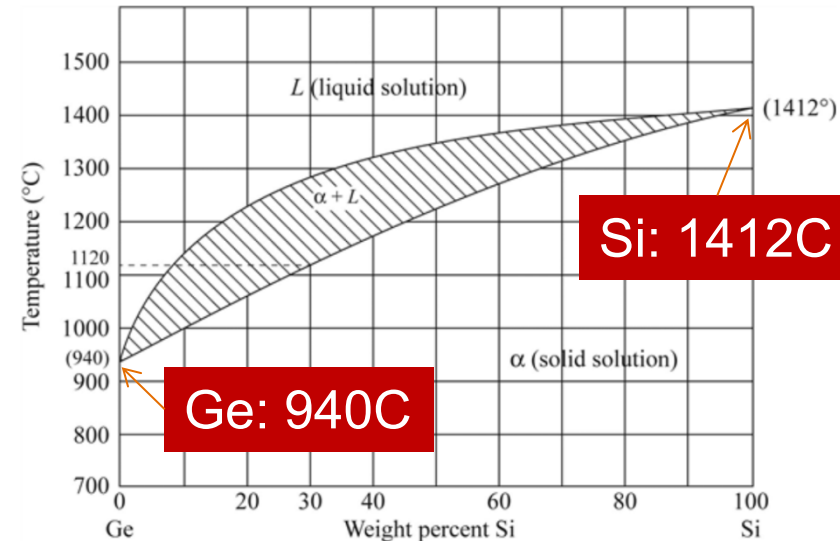
NEW CHANNEL MATERIALS DRIVING LOWER THERMAL BUDGET

› Thermal budget is squeezed in the middle

- Ge melting point is 940C versus 1412C for Si; many more process steps
- Need for low temperature high quality materials

› Example: SiN for gate spacer

- Batch LPCVD: DCS + NH₃ @ 650~750C
- Batch ALD: DCS + NH₃ @ 500~650C
- Single wafer PEALD: novel precursors @ 350 to 550C



NEEDS FROM CHEMICAL SUPPLIERS

DRIVE INNOVATION • DELIVER EXCELLENCE 

› **Novel materials**

- Precursors for low-resistivity metals, ternary films with incorporation from the precursor as part of deposition process
- Highly reactive precursors that can enable fast film closure

› **Precursors with high reactivity at low temperature**

- New materials are driving FEOL processes toward 400C
- Enabling low-T processes for existing materials like SiO and SiN

› **Chemicals that do not easily decompose even with long residence times in reactors for high-aspect ratio structures**

- Solid precursors, lower-volatility liquids

› **Enable faster development cycle by doing more in-house pre-screening**

- Representative reactors and structures to show upfront feasibility for step coverage, utilization, efficiency of incorporation

› **Moore's Law is increasingly a materials play**

- Enabling materials such as HfO₂, ZrO₂, Si:Ge, Si:P, Co, ...
- Enabling processes for existing materials like LT SiO and SiN

› **New device architectures and EUV will drive stronger need for flexible chemistries and film properties**

› **Selective deposition in various combinations of surface and film type will be required**

› **Many opportunities for enabling materials solutions with innovative chemistries**

Thanks for your attention!

- › Thanks to Ivo Raaijmakers, Bob Hollands, Bert Jongbloed, Jan Willem Maes, John Cossins, Hessel Sprey, and many others for providing material, and their help in preparing, for this presentation